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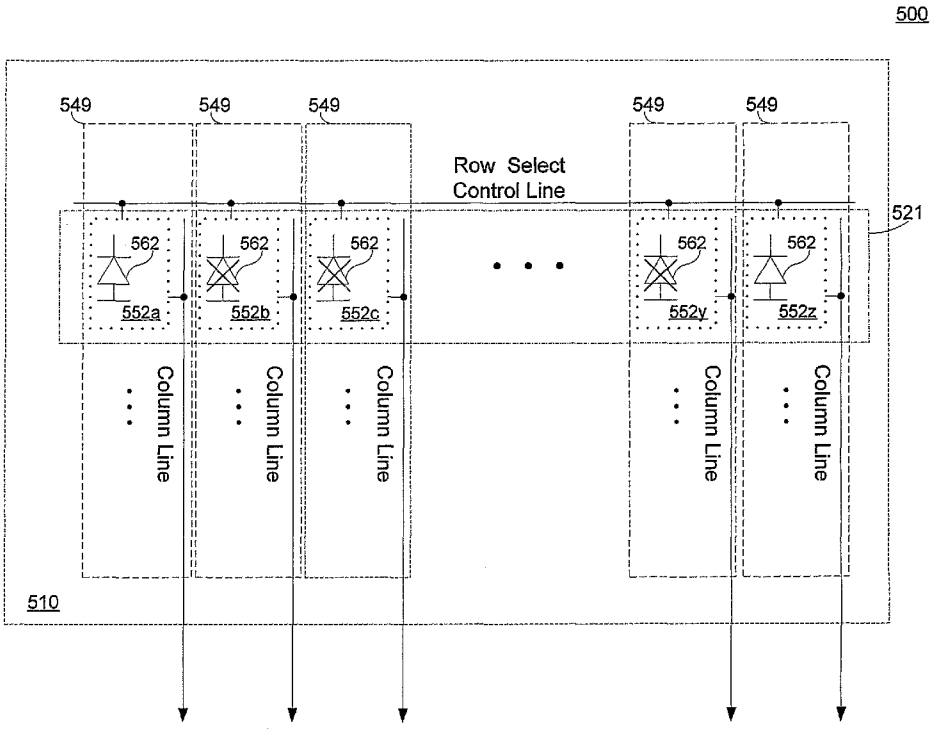
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(54) Title: PHOTO DIODE FUSE-ID FOR CMOS IMAGERS



(57) Abstract: A CMOS image pixel array formed on a chip is used for storing programmed information within the pixel array. Manufacturing lot and other data is written to the array during manufacturing and testing by applying a laser to pixels to render the photodiode defective. The programmed data is read from the pixel array using existing circuitry.

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